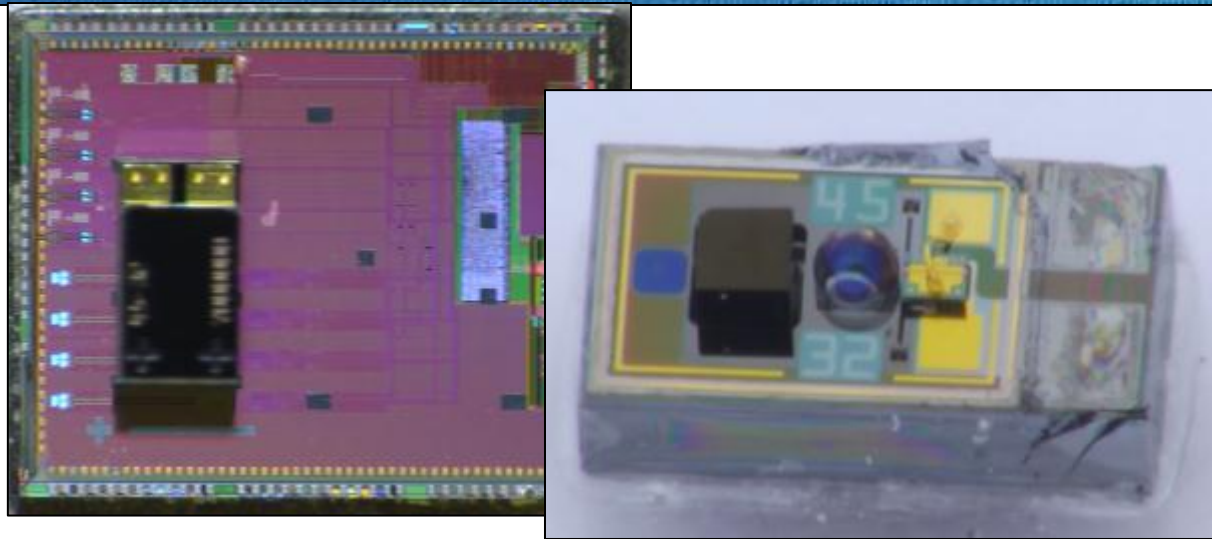


# Reverse Costing analysis



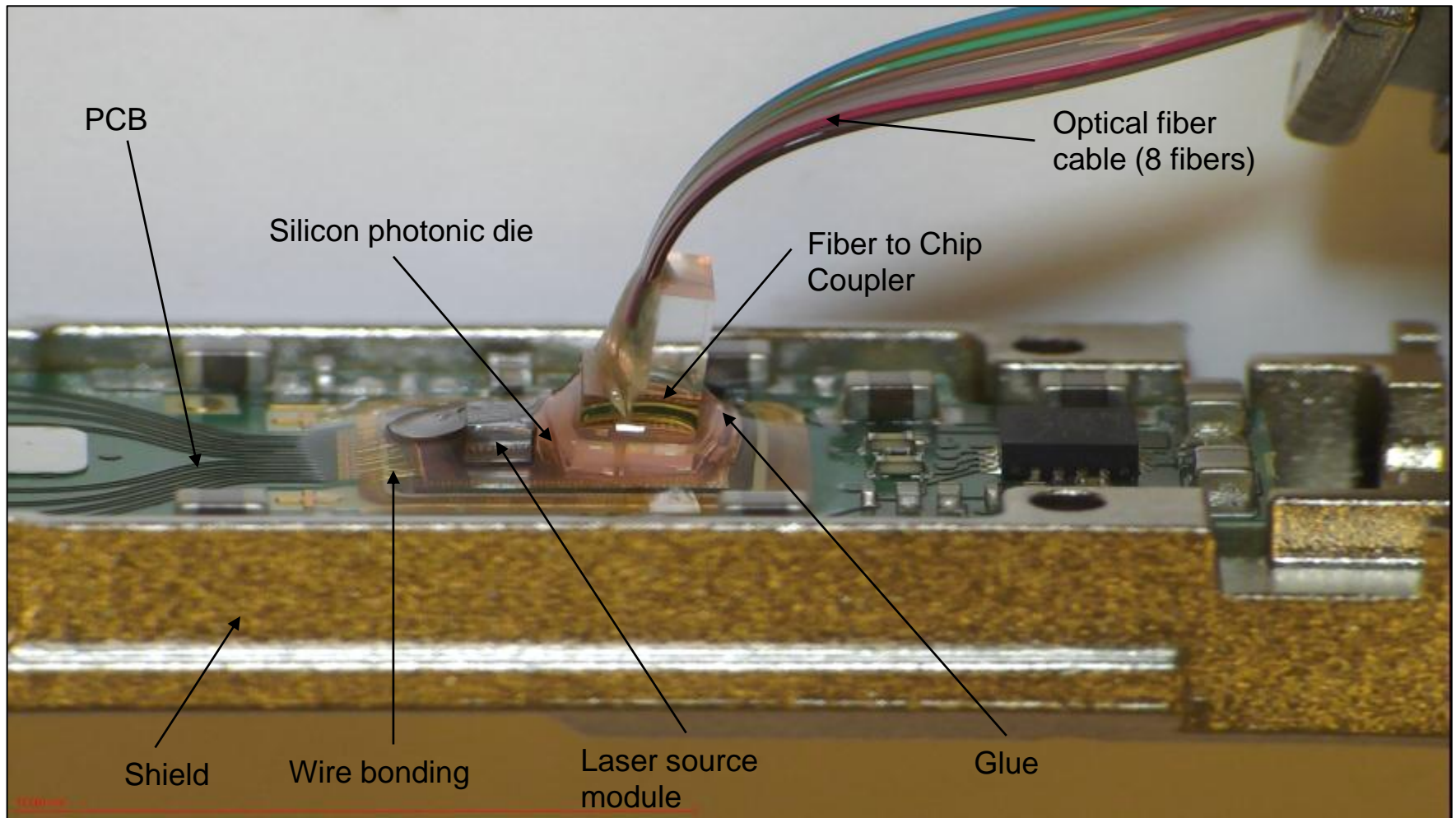
## **Molex Active Optical Cable Luxtera Silicon Photonic Chip + MEMS Laser Source Module**

November 2012- Version 1

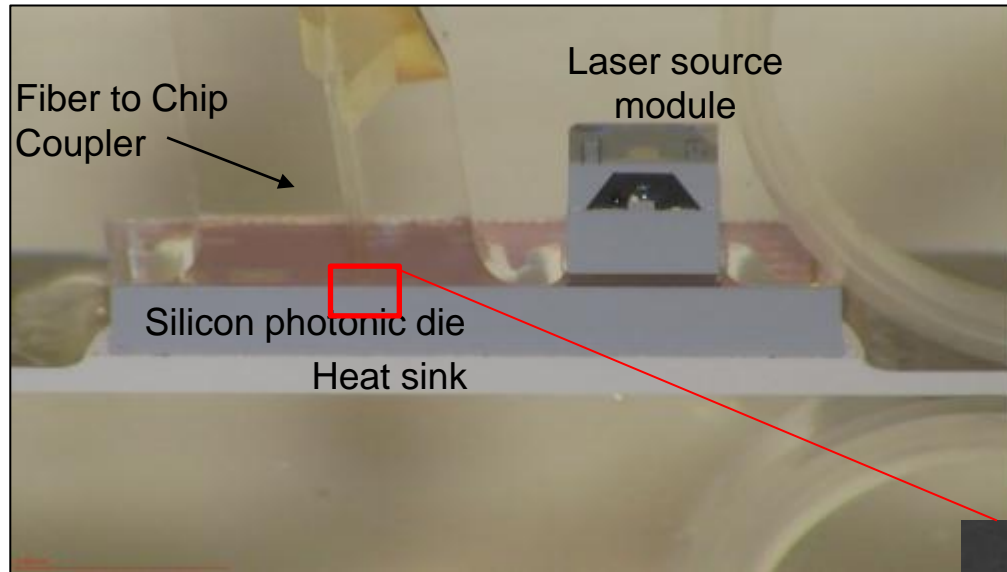
Written by: Sylvain HALLEREAU

DISCLAIMER : System Plus Consulting provides cost studies based on its knowledge of the manufacturing and selling prices of electronic components and systems. The given values are realistic estimates which do not bind System Plus Consulting nor the manufacturers quoted in the report. System Plus Consulting is in no case responsible for the consequences related to the use which is made of the contents of this report. The quoted trademarks are property of their owners.

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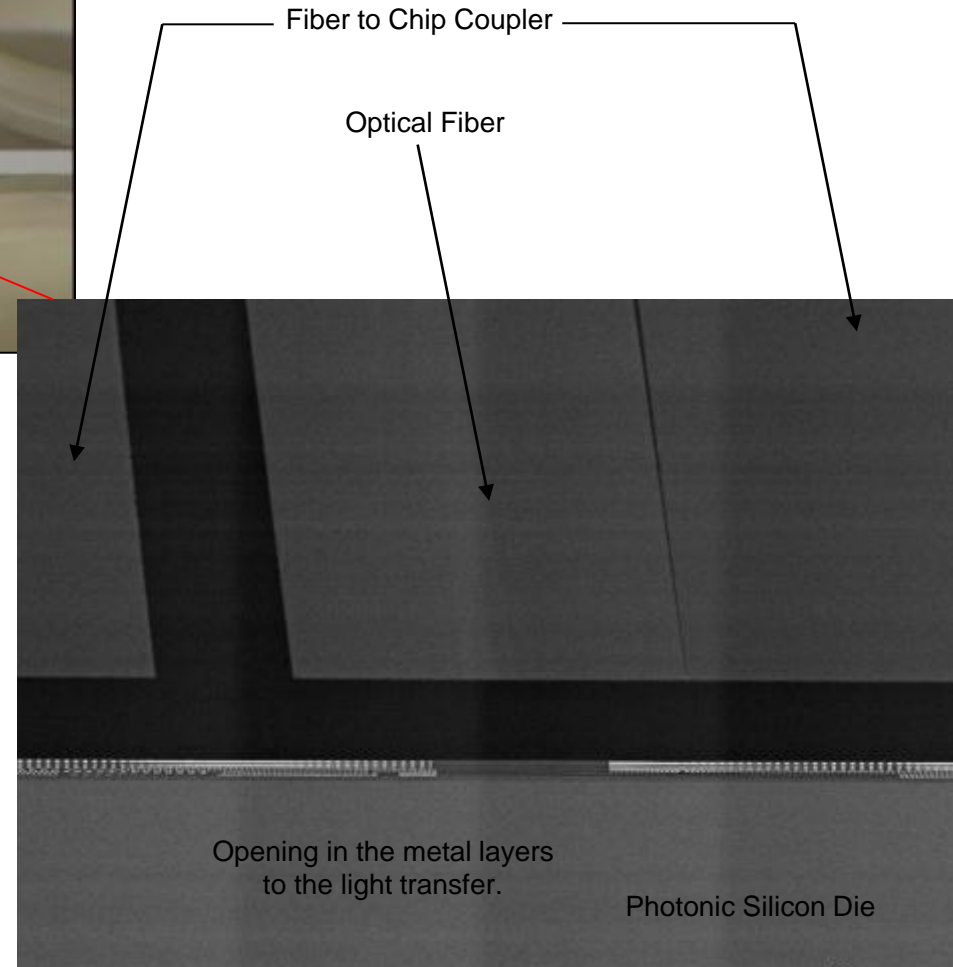


*Optical fiber coupling – tilted view*



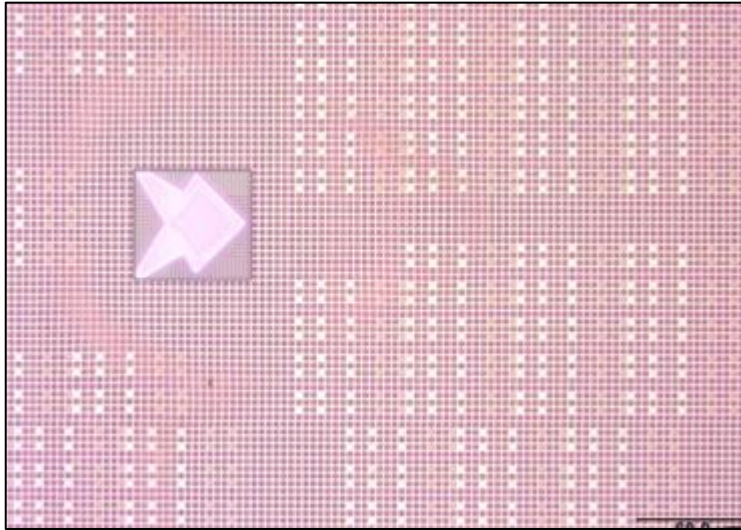
**System cross-section : Optical View**

- The Fiber to Chip Coupler is composed of two plastic parts. The small part has 8 grooves to hold the optical fibers.

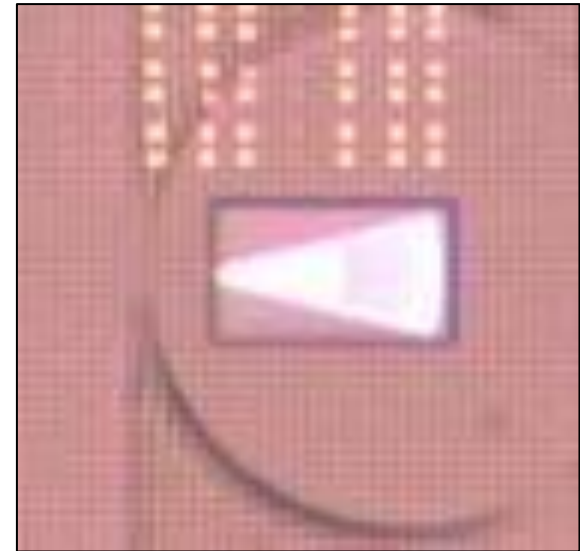


**Detail cross section : SEM view**

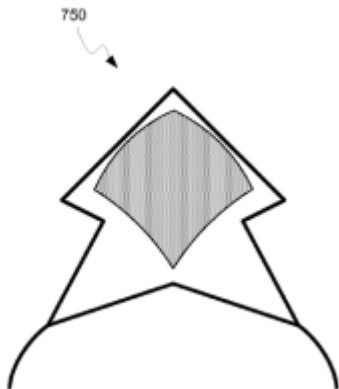




***Polarization Splitting Grating Coupler (PSGC)***



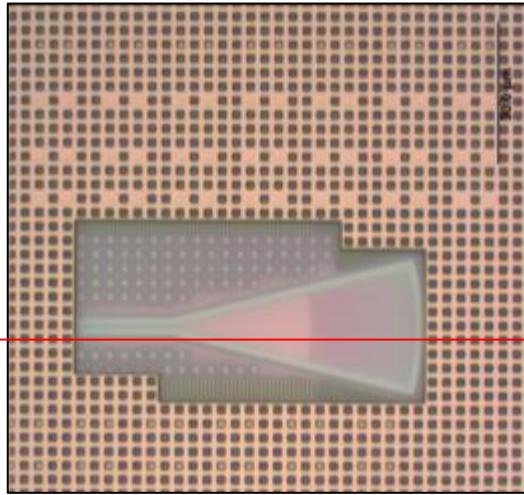
***Output light grating coupler***



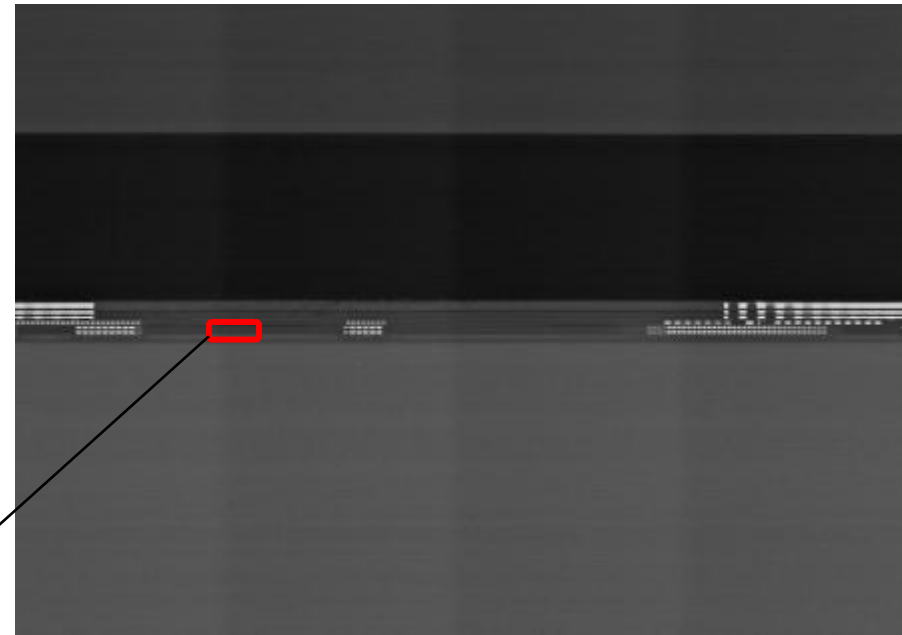
The PSGC may enable the coupling of an incoming light signal and generating 2 signals in the silicon waveguide.

The grating coupler may enable to emit the light toward the optical fibers.

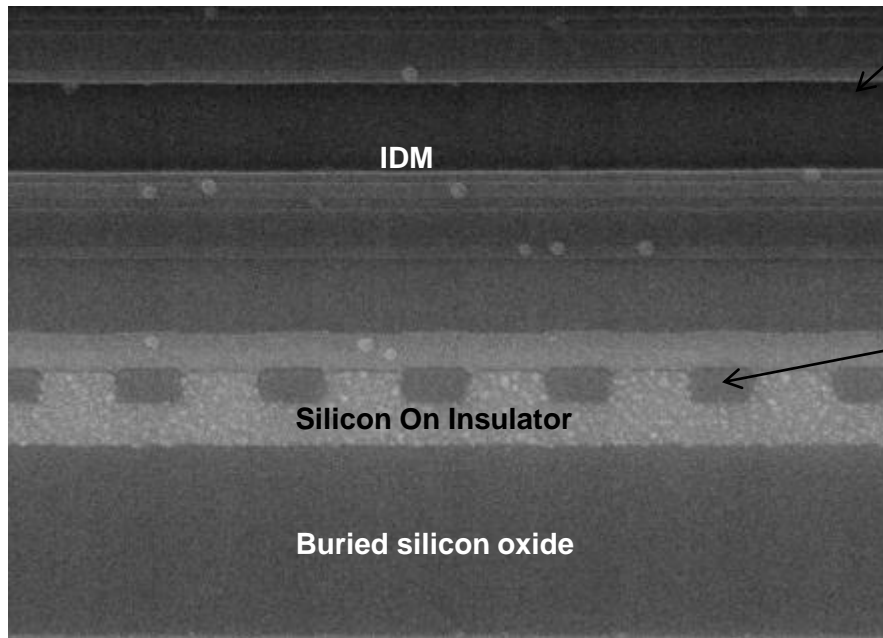
***Fig. 7 patent WO xxxxxxxxx***



**Cross-section**



**Grating Coupler - Cross-section**

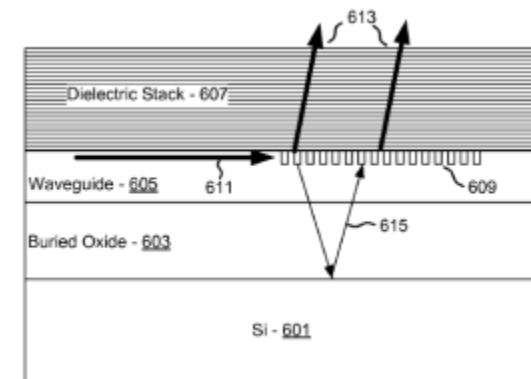


IDM

Silicon oxide

Silicon On Insulator

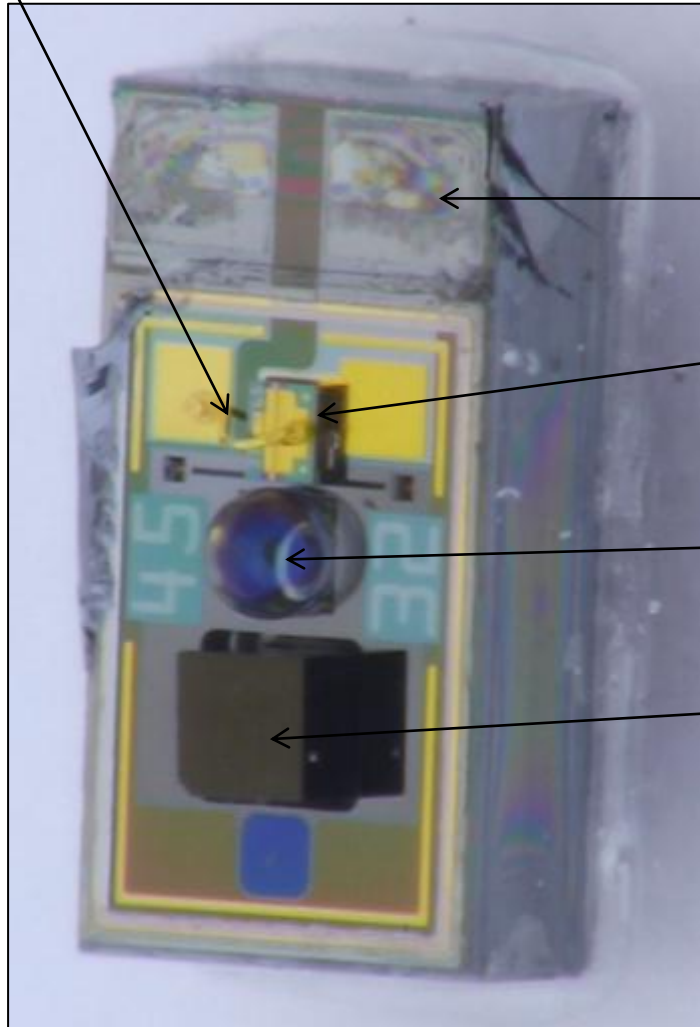
Buried silicon oxide



**Fig. 6 patent WO xxxxxxxx**

**Detail Grating Coupler - Cross-section**

Ball Lens



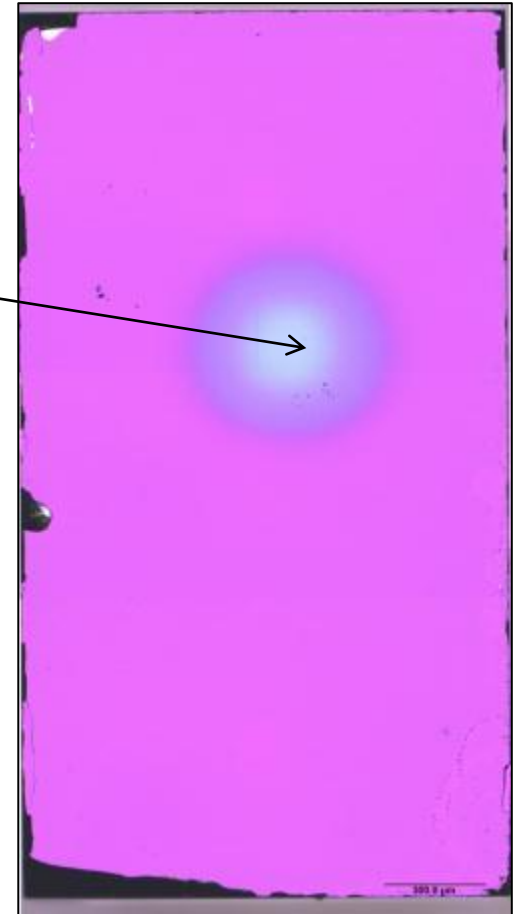
Laser Module after Lid removed : Optical view

Pad

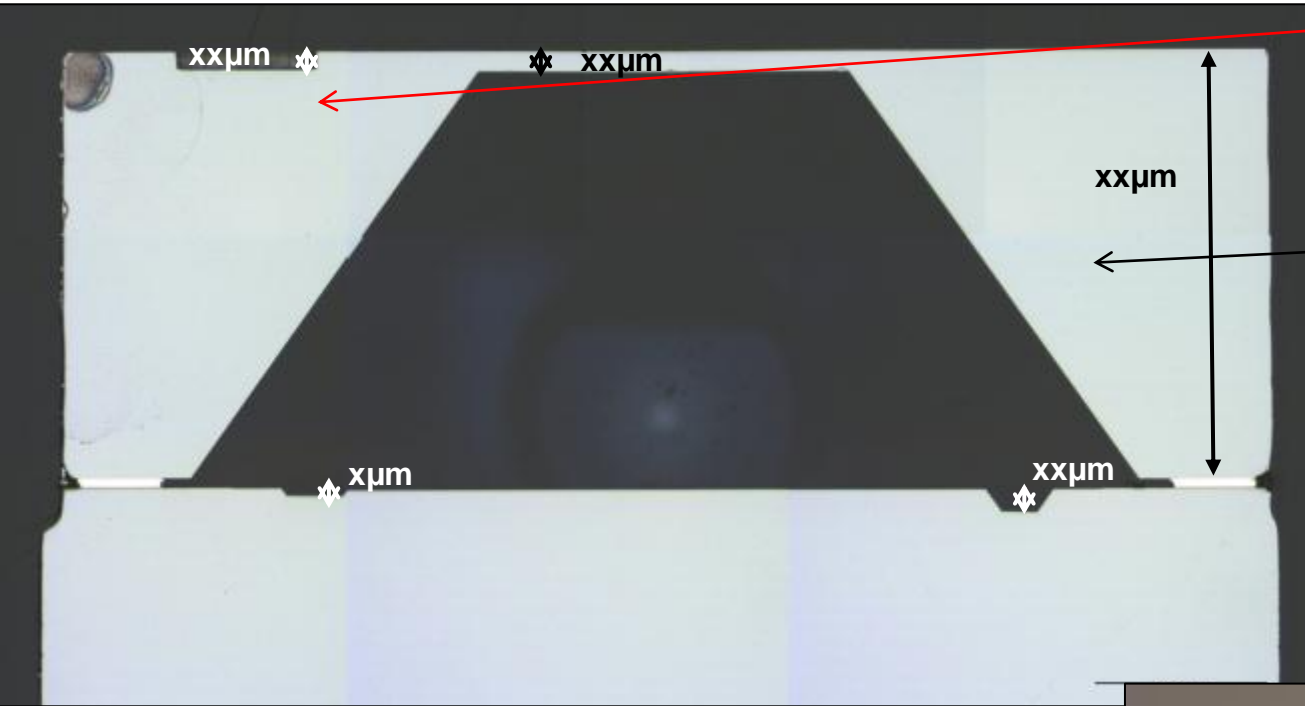
1550nm  
diode laser

Ball Lens

Rotator isolator



Photonic die side of the Laser Module

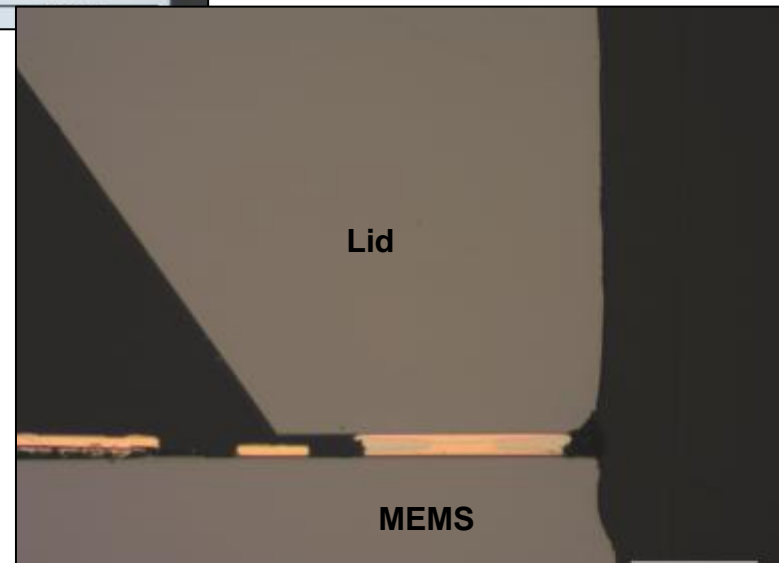


Mark on the top etched in the silicon

Lid Thickness :  $xx\mu\text{m}$

*Lid cross-section : Optical view*

The Lid and the MEMS are sealed using gold solder.

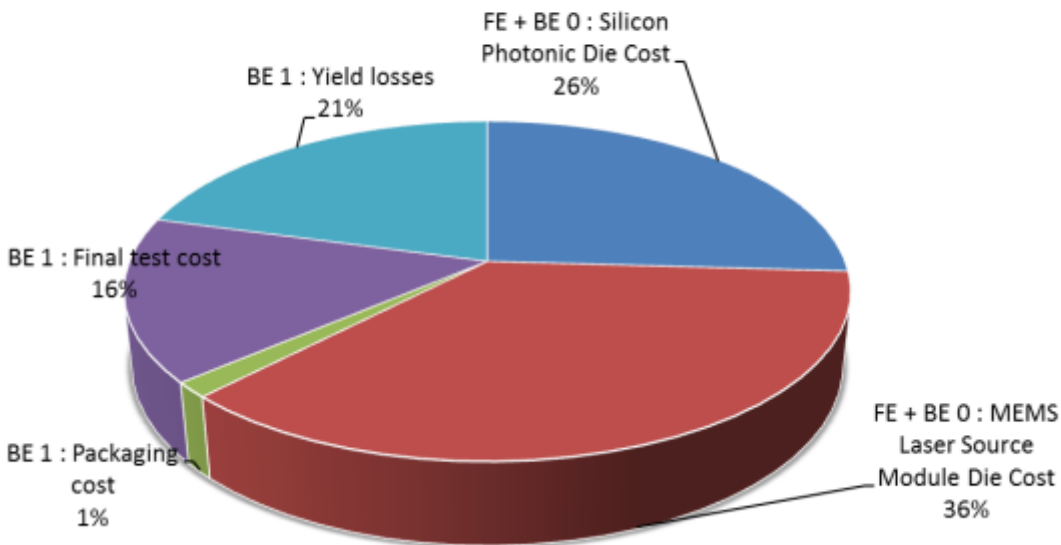


**Metallic sealing**



	Low Yield		Medium Yield		High Yield	
	Cost	Breakdown	Cost	Breakdown	Cost	Breakdown
FE + BE 0 : Silicon Photonic Die Cost						
FE + BE 0 : MEMS Laser Source Module Die Cost						
BE 1 : Packaging cost						
BE 1 : Final test cost						
BE 1 : Yield losses						
<b>40Gbps Photonic component cost</b>	<b>\$0,000</b>	<b>0%</b>	<b>\$0,000</b>	<b>0%</b>	<b>\$0,000</b>	<b>0%</b>

Component Cost Breakdown (Medium Yields)



- The final die cost ranges from \$xxx to \$xxx according to yield variations.
- The back-end 0 cost (probe test and dicing) represents x% of the cost of the die.
- The yield losses costs due to probe and dicing represents xx% of the total manufacturing cost.
  - The die cost includes the rejects at probe test and dicing.
  - The yield losses represents the defective dies which are rejected.

- This reverse costing analysis represents the best cost/price evaluation given the publically available data, completed with industry expert estimates.
- Given the hypothesis presented in this analysis the major sources of correction would lead to a +/- 10% correction on the manufacturing cost (if all parameters are cumulated)
  - **IC** +/- **8%**
  - **MEMS** +/- **5%**
  - **Optical** +/- **10%**
  - **Test** +/- **20%**
- These results are open for discussion. We can re-evaluate this circuit with your information. Please contact us:



Headquarters :

Address :  
21 rue La Noue Bras de Fer  
F-44200 Nantes  
FRANCE

Tel +33 (0)240 180 916  
Fax +33 (0)253 551 059

info@systemplus.fr




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EUROPE Sales Office  
Ms Lizzie LEVENEZ  
Frankfurt am Main  
Tel: +49 (0) 151 23 54 41 82  
Email : llevenez@systemplus.fr

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